



[illegible]

10669443

LEE, JEONG SIK

Haney, Richale L

3765

Richale L. Haney (Assistant Examiner)	1/3/2007 (Date)	 GARY L. WELCH SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700	Total Claims Allowed: 19	
 (Legal Instruments Examiner)	1/8/07 (Date)		(Primary Examiner)	O.G. Print Claim(s) 1